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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

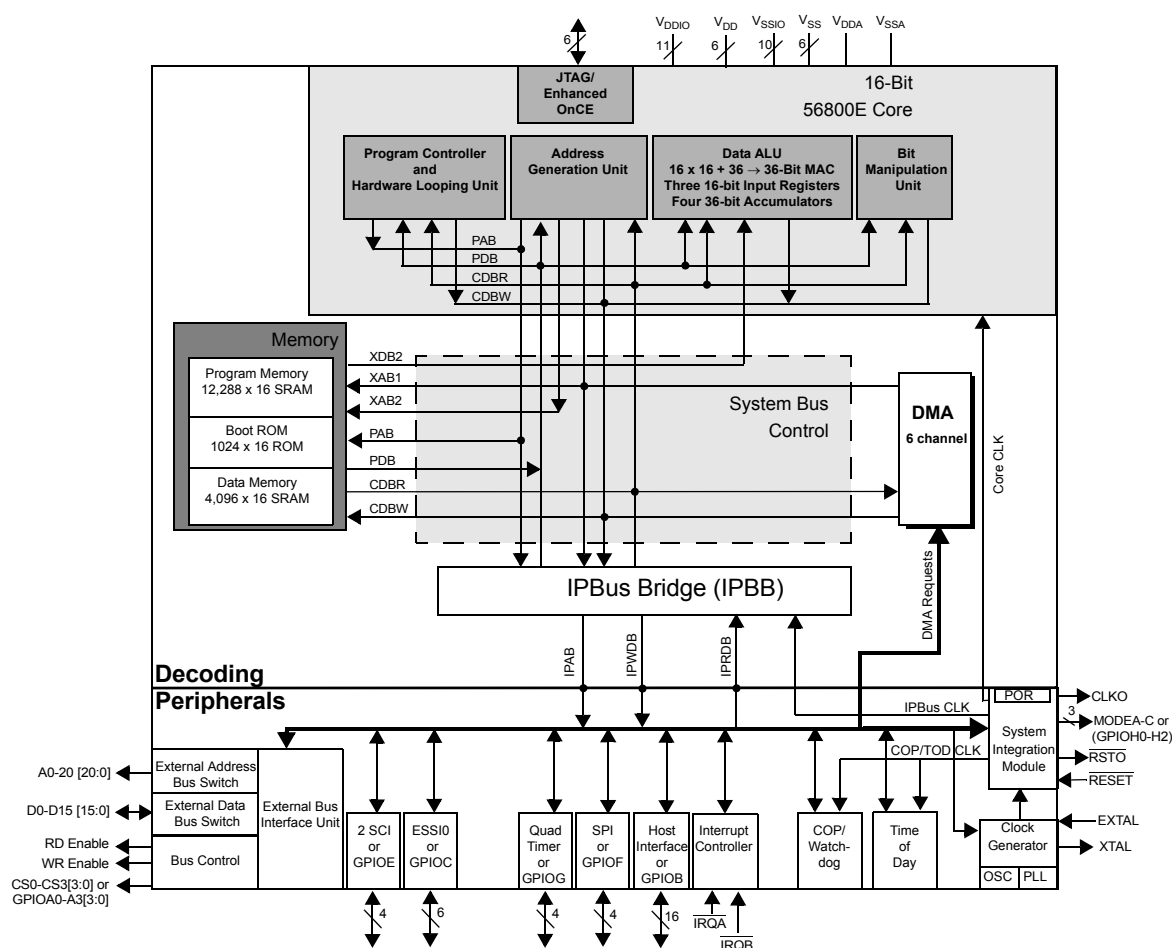
Applications of "[Embedded - Microcontrollers](#)"

Details

| | |
|----------------------------|---|
| Product Status | Obsolete |
| Core Processor | 56800E |
| Core Size | 16-Bit |
| Speed | 120MHz |
| Connectivity | EBI/EMI, SCI, SPI, SSI |
| Peripherals | DMA, POR, WDT |
| Number of I/O | 41 |
| Program Memory Size | 24KB (12K x 16) |
| Program Memory Type | SRAM |
| EEPROM Size | - |
| RAM Size | 4K x 16 |
| Voltage - Supply (Vcc/Vdd) | 1.62V ~ 1.98V |
| Data Converters | - |
| Oscillator Type | External |
| Operating Temperature | -40°C ~ 85°C (TA) |
| Mounting Type | Surface Mount |
| Package / Case | 128-LQFP |
| Supplier Device Package | 128-LQFP (14x20) |
| Purchase URL | https://www.e-xfl.com/product-detail/nxp-semiconductors/dsp56853fge |

56853 General Description

- 120 MIPS at 120MHz
- 12K x 16-bit Program SRAM
- 4K x 16-bit Data SRAM
- 1K x 16-bit Boot ROM
- Access up to 2M words of program memory or 8M of data memory
- Chip Select Logic for glue-less interface to ROM and SRAM
- Six (6) independent channels of DMA
- Enhanced Synchronous Serial Interfaces (ESSI)
- Two (2) Serial Communication Interfaces (SCI)
- Serial Port Interface (SPI)
- 8-bit Parallel Host Interface
- General Purpose 16-bit Quad Timer
- JTAG/Enhanced On-Chip Emulation (OnCE™) for unobtrusive, real-time debugging
- Computer Operating Properly (COP)/Watchdog Timer
- Time-of-Day (TOD)
- 128 LQFP package
- Up to 41 GPIO



56853 Block Diagram

Part 1 Overview

1.1 56853 Features

1.1.1 Core

- Efficient 16-bit engine with dual Harvard architecture
- 120 Million Instructions Per Second (MIPS) at 120MHz core frequency
- Single-cycle 16×16 -bit parallel Multiplier-Accumulator (MAC)
- Four (4) 36-bit accumulators including extension bits
- 16-bit bidirectional shifter
- Parallel instruction set with unique DSP addressing modes
- Hardware DO and REP loops
- Three (3) internal address buses and one (1) external address bus
- Four (4) internal data buses and one (1) external data bus
- Instruction set supports both DSP and controller functions
- Four (4) hardware interrupt levels
- Five (5) software interrupt levels
- Controller-style addressing modes and instructions for compact code
- Efficient C Compiler and local variable support
- Software subroutine and interrupt stack with depth limited only by memory
- JTAG/Enhanced OnCE debug programming interface

1.1.2 Memory

- Harvard architecture permits up to three (3) simultaneous accesses to program and data memory
- On-Chip Memory
 - $12K \times 16$ -bit Program SRAM
 - $4K \times 16$ -bit Data SRAM
 - $1K \times 16$ -bit Boot ROM
- Off-Chip Memory Expansion (EMI)
 - Access up to 2M words of program memory or 8M data memory
 - Chip Select Logic for glue-less interface to ROM and SRAM

1.1.3 Peripheral Circuits for 56853

- General Purpose 16-bit Quad Timer*
- Two (2) Serial Communication Interfaces (SCI)*
- Serial Peripheral Interface (SPI) Port*
- Enhanced Synchronous Serial Interface (ESSI) modules*
- Computer Operating Properly (COP)

- Watchdog Timer
- JTAG/Enhanced On-Chip Emulation (OnCE) for unobtrusive, real-time debugging
- Six (6) independent channels of DMA
- 8-bit Parallel Host Interface*
- Time-of-Day (TOD)
- 128 LQFP package
- Up to 41 GPIO

* Each peripheral I/O can be used alternately as a General Purpose I/O if not needed

1.1.4 Energy Information

- Fabricated in high-density CMOS with 3.3V, TTL-compatible digital inputs
- Wait and Stop modes available

1.2 56853 Description

The 56853 is a member of the 56800E core-based family of controllers. It combines, on a single chip, the processing power of a Digital Signal Processor (DSP) and the functionality of a microcontroller with a flexible set of peripherals to create an extremely cost-effective solution. Because of its low cost, configuration flexibility, and compact program code, the 56853 is well-suited for many applications. The 56853 includes many peripherals that are especially useful for low-end Internet appliance applications and low-end client applications such as telephony; portable devices; Internet audio and point-of-sale systems, such as noise suppression; ID tag readers; sonic/subsonic detectors; security access devices; remote metering; sonic alarms.

The 56800E core is based on a Harvard-style architecture consisting of three execution units operating in parallel, allowing as many as six operations per instruction cycle. The microprocessor-style programming model and optimized instruction set allow straightforward generation of efficient, compact DSP and control code. The instruction set is also highly efficient for C Compilers, enabling rapid development of optimized control applications.

The 56853 supports program execution from either internal or external memories. Two data operands can be accessed from the on-chip Data RAM per instruction cycle. The 56853 also provides two external dedicated interrupt lines, and up to 41 General Purpose Input/Output (GPIO) lines, depending on peripheral configuration.

The 56853 controller includes 12K words of Program RAM, 4K words of Data RAM, and 1K words of Boot ROM. It also supports program execution from external memory. The 56800 core can access two data operands from the on-chip Data RAM per instruction cycle.

This controller also provides a full set of standard programmable peripherals that include an 8-bit parallel Host Interface, Enhanced Synchronous Serial Interface (ESSI), one Serial Peripheral Interface (SPI), the option to select a second SPI or two Serial Communications Interfaces (SCIs), and Quad Timer. The Host Interface, ESSI, SPI, SCI, four chip selects and quad timer can be used as General Purpose Input/Outputs (GPIOs) if its primary function is not required.

1.5 Data Sheet Conventions

This data sheet uses the following conventions:

OVERBAR This is used to indicate a signal that is active when pulled low. For example, the **RESET** pin is active when low.

“asserted” A high true (active high) signal is high or a low true (active low) signal is low.

“deasserted” A high true (active high) signal is low or a low true (active low) signal is high.

| Examples: | Signal/Symbol | Logic State | Signal State | Voltage ¹ |
|-----------|-------------------------|-------------|--------------|-------------------------------|
| | $\overline{\text{PIN}}$ | True | Asserted | $V_{\text{IL}}/V_{\text{OL}}$ |
| | $\overline{\text{PIN}}$ | False | Deasserted | $V_{\text{IH}}/V_{\text{OH}}$ |
| | PIN | True | Asserted | $V_{\text{IH}}/V_{\text{OH}}$ |
| | PIN | False | Deasserted | $V_{\text{IL}}/V_{\text{OL}}$ |

1. Values for VIL, VOL, VIH, and VOH are defined by individual product specifications.

Part 2 Signal/Connection Descriptions

2.1 Introduction

The input and output signals of the 56853 are organized into functional groups, as shown in [Table 2-1](#) and as illustrated in [Figure 2-1](#). In [Table 3-1](#) each table row describes the package pin and the signal or signals present.

Table 2-1 56853 Functional Group Pin Allocations

| Functional Group | Number of Pins |
|---|-------------------------|
| Power (V_{DD} , V_{DDIO} , or V_{DDA}) | (6, 11, 1) ¹ |
| Ground (V_{SS} , V_{SSIO} , or V_{SSA}) | (6, 10, 1) ¹ |
| PLL and Clock | 3 |
| External Bus Signals | 39 |
| External Chip Select* | 4 |
| Interrupt and Program Control | 7 ² |
| Host Interface (HI)* | 16 ³ |
| Enhanced Synchronous Serial Interface (ESSIO) Port* | 6 |
| Serial Communications Interface (SCI0) Ports* | 2 |
| Serial Communications Interface (SCI1) Ports* | 2 |
| Serial Peripheral Interface (SPI) Port* | 4 |
| Quad Timer Module Port* | 4 |
| JTAG/Enhanced On-Chip Emulation (EOnCE) | 6 |

*Alternately, GPIO pins

1. $V_{DD} = V_{DD\text{ CORE}}$, $V_{SS} = V_{SS\text{ CORE}}$, $V_{DDIO} = V_{DD\text{ IO}}$, $V_{SSIO} = V_{SS\text{ IO}}$, $V_{DDA} = V_{DD\text{ ANA}}$, $V_{SSA} = V_{SS\text{ ANA}}$
2. MODA, MODB and MODC can be used as GPIO after the bootstrap process has completed.
3. The following Host Interface signals are multiplexed: \overline{HRWB} to \overline{HRD} , \overline{HDS} to \overline{HWR} , \overline{HREQ} to \overline{HTRQ} and \overline{HACK} to \overline{HRRQ} .

Table 3-1. 56853 Signal and Package Information for the 128-pin LQFP (Continued)

| Pin No. | Signal Name | Type | Description |
|---------|--------------------------|-------------------|--|
| 106 | $\overline{\text{HACK}}$ | Input | Host Acknowledge ($\overline{\text{HACK}}$) —When the HI08 is programmed for HRMS=0 functionality (typically used on a single-data-strobe bus), this input has two functions: (1) provide a Host Acknowledge signal for DMA transfers or (2) to control handshaking and provide a Host Interrupt Acknowledge compatible with the MC68000 family processors. These pins are disconnected internally. |
| | HRRQ | Open Drain Output | Receive Host Request (HRRQ) —This signal is the Receive Host Request output when the HI08 is programmed for HRMS=1 functionality and is typically used on a double-data-strobe bus. |
| | GPIOB15 | Input/Output | Port B GPIO(15) —This pin is a General Purpose I/O (GPIO) pin when not configured for host port usage. |
| 101 | TIO0 | Input/Output | Timer Input/Outputs (TIO0) —This pin can be independently configured to be either a timer input source or an output flag. |
| | GPIOG0 | Input/Output | Port G GPIOG0 —This pin is a General Purpose I/O (GPIO) pin that can individually be programmed as an input or output pin. |
| 99 | TIO1 | Input/Output | Timer Input/Outputs (TIO1) —This pin can be independently configured to be either a timer input source or an output flag. |
| | GPIOG1 | Input/Output | Port G GPIO (1) —This pin is a General Purpose I/O (GPIO) pin that can individually be programmed as an input or output pin. |
| 98 | TIO2 | Input/Output | Timer Input/Outputs (TIO2) —This pin can be independently configured to be either a timer input source or an output flag. |
| | GPIOG2 | Input/Output | Port G GPIO (2) —This pin is a General Purpose I/O (GPIO) pin that can individually be programmed as an input or output pin. |
| 97 | TIO3 | Input/Output | Timer Input/Outputs (TIO3) —This pin can be independently configured to be either a timer input source or an output flag. |
| | GPIOG3 | Input/Output | Port G GPIO (3) —This pin is a General Purpose I/O (GPIO) pin that can individually be programmed as an input or output pin. |
| 20 | $\overline{\text{IRQA}}$ | Input | External Interrupt Request A and B —The IRQA and IRQB inputs are asynchronous external interrupt requests that indicate that an external device is requesting service. A Schmitt trigger input is used for noise immunity. They can be programmed to be level-sensitive or negative-edge- triggered. If level-sensitive triggering is selected, an external pull-up resistor is required for Wired-OR operation. |
| 21 | $\overline{\text{IRQB}}$ | | |
| 15 | MODA | Input | Mode Select (MODA) —During the bootstrap process MODA selects one of the eight bootstrap modes. |
| | GPIOH0 | Input/Output | Port H GPIO (0) —This pin is a General Purpose I/O (GPIO) pin after the bootstrap process has completed. |

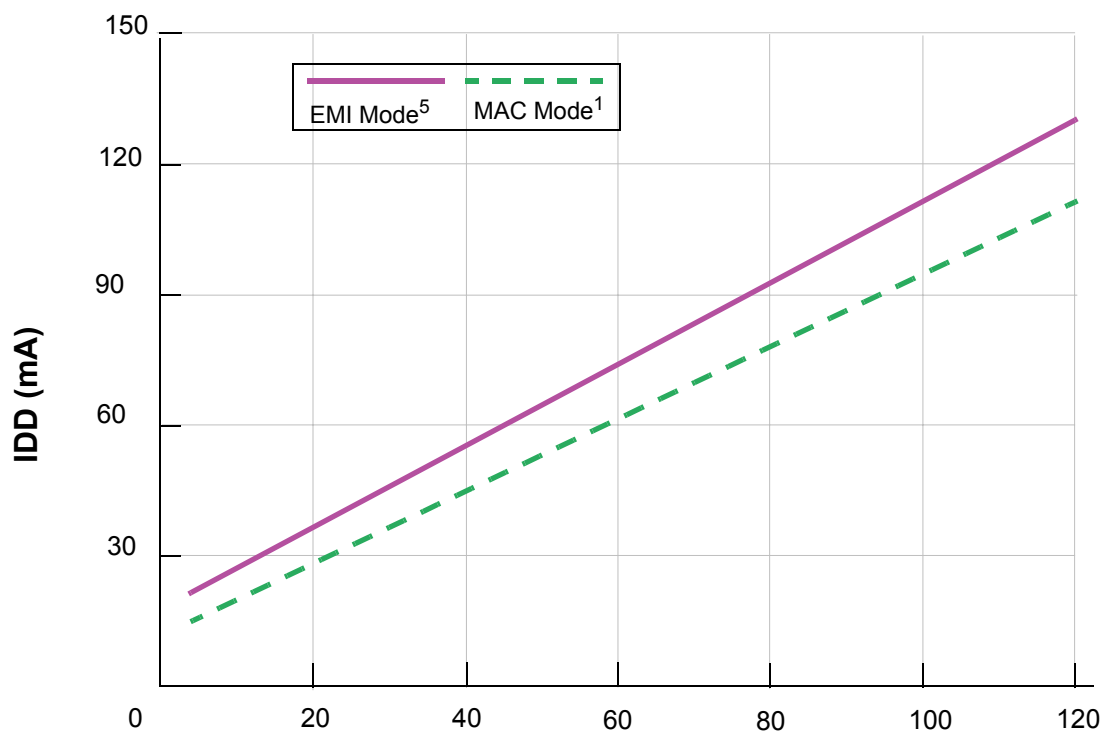


Figure 4-1 Maximum Run $I_{DDTOTAL}$ vs. Frequency (see Notes 1. and 5. in Table 4-4)

Table 4-6 PLL Timing

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{C}$, $C_L \leq 50\text{ pF}$, $f_{op} = 120\text{ MHz}$

| Characteristic | Symbol | Min | Typ | Max | Unit |
|---|------------|-----|-----|-----|------|
| External reference crystal frequency for the PLL ¹ | f_{osc} | 2 | 4 | 4 | MHz |
| PLL output frequency | f_{clk} | 40 | — | 240 | MHz |
| PLL stabilization time ² | t_{plls} | — | 1 | 10 | ms |

1. An externally supplied reference clock should be as free as possible from any phase jitter for the PLL to work correctly. The PLL is optimized for 4MHz input crystal.
2. This is the minimum time required after the PLL setup is changed to ensure reliable operation.

4.6 External Memory Interface Timing

The External Memory Interface is designed to access static memory and peripheral devices. [Figure 4-10](#) shows sample timing and parameters that are detailed in [Table 4-7](#).

The timing of each parameter consists of both a fixed delay portion and a clock related portion; as well as user controlled wait states. The equation:

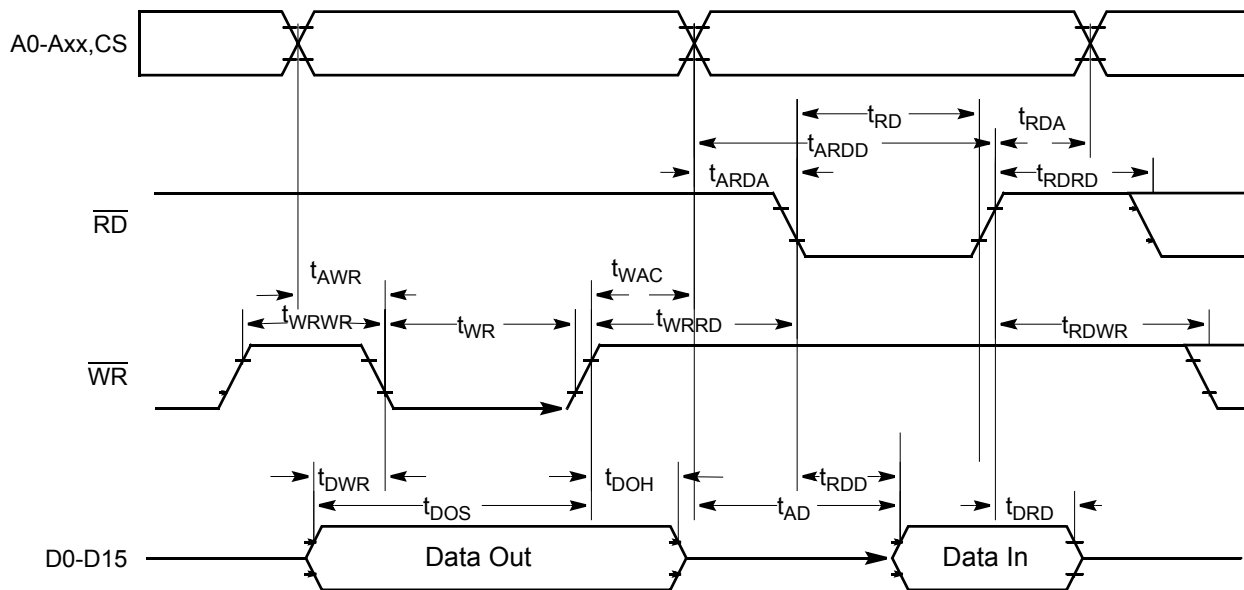
$$t = D + P * (M + W)$$

should be used to determine the actual time of each parameter. The terms in the above equation are defined as:

- t parameter delay time
- D fixed portion of the delay, due to on-chip path delays.
- P the period of the system clock, which determines the execution rate of the part (i.e. when the device is operating at 120 MHz, $P = 8.33\text{ ns}$).
- M Fixed portion of a clock period inherent in the design. This number is adjusted to account for possible clock duty cycle derating.
- W the sum of the applicable wait state controls. See the “Wait State Controls” column of [Table 4-7](#) for the applicable controls for each parameter. See the EMI chapter of the 83x Peripheral Manual for details of what each wait state field controls.

Some of the parameters contain two sets of numbers. These parameters have two different paths and clock edges that must be considered. Check both sets of numbers and use the smaller result. The appropriate entry may change if the operating frequency of the part changes.

The timing of write cycles is different when $WWS = 0$ than when $WWS > 0$. Therefore, some parameters contain two sets of numbers to account for this difference. The “Wait States Configuration” column of [Table 4-7](#) should be used to make the appropriate selection.



Note: During read-modify-write instructions and internal instructions, the address lines do not change state.

Figure 4-10 External Memory Interface Timing

Table 4-7 External Memory Interface Timing

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{C to } +120^\circ\text{C}$, $C_L \leq 50\text{ pF}$, $P = 8.333\text{ ns}$

| Characteristic | Symbol | Wait States Configuration | D | M | Wait States Controls | Unit |
|--|-----------|---------------------------|-------|------|----------------------|------|
| Address Valid to \overline{WR} Asserted | t_{AWR} | WWS=0 | -0.79 | 0.50 | WWSS | ns |
| | | WWS>0 | -1.98 | 0.69 | | |
| \overline{WR} Width Asserted to \overline{WR} Deasserted | t_{WR} | WWS=0 | -0.86 | 0.19 | WWS | ns |
| | | WWS>0 | -0.01 | 0.00 | | |
| Data Out Valid to \overline{WR} Asserted | t_{DWR} | WWS=0 | -1.52 | 0.00 | WWSS | ns |
| | | WWS=0 | -5.69 | 0.25 | | |
| | | WWS>0 | -2.10 | 0.19 | | |
| | | WWS>0 | -4.66 | 0.50 | | |
| Valid Data Out Hold Time after \overline{WR} Deasserted | t_{DOH} | | -1.47 | 0.25 | WWSH | ns |
| Valid Data Out Set Up Time to \overline{WR} Deasserted | t_{DOS} | | -2.36 | 0.19 | WWS, WWSS | ns |
| | | | -4.67 | 0.50 | | |
| Valid Address after \overline{WR} Deasserted | t_{WAC} | | -1.60 | 0.25 | WWSH | |

Table 4-7 External Memory Interface Timing (Continued)

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{C}$, $C_L \leq 50\text{ pF}$, $P = 8.333\text{ ns}$

| Characteristic | Symbol | Wait States Configuration | D | M | Wait States Controls | Unit |
|--|-------------------|---------------------------|--------------------|------------------|-------------------------|------|
| $\overline{\text{RD}}$ Deasserted to Address Invalid | t_{RDA} | | - 0.44 | 0.00 | RWSH | ns |
| Address Valid to $\overline{\text{RD}}$ Deasserted | t_{ARDD} | | -2.07 | 1.00 | RWSS,RWS | ns |
| Valid Input Data Hold after $\overline{\text{RD}}$ Deasserted | t_{DRD} | | 0.00 | N/A ¹ | — | ns |
| $\overline{\text{RD}}$ Assertion Width | t_{RD} | | -1.34 | 1.00 | RWS | ns |
| Address Valid to Input Data Valid | t_{AD} | | -10.27 | 1.00 | RWSS,RWS | ns |
| | | | -13.5 | 1.19 | | |
| Address Valid to $\overline{\text{RD}}$ Asserted | t_{ARDA} | | - 0.94 | 0.00 | RWSS | ns |
| $\overline{\text{RD}}$ Asserted to Input Data Valid | t_{RDD} | | -9.53 | 1.00 | RWSS,RWS | ns |
| | | | -12.64 | 1.19 | | |
| $\overline{\text{WR}}$ Deasserted to $\overline{\text{RD}}$ Asserted | t_{WRRD} | | -0.75 | 0.25 | WWSH,RWSS | ns |
| $\overline{\text{RD}}$ Deasserted to $\overline{\text{RD}}$ Asserted | t_{RDRD} | | -0.16 ² | 0.00 | RWSS,RWSH | ns |
| $\overline{\text{WR}}$ Deasserted to $\overline{\text{WR}}$ Asserted | t_{WRWR} | WWS=0 | -0.44 | 0.75 | WWSS, WWSH | ns |
| | | WWS>0 | -0.11 | 1.00 | | |
| $\overline{\text{RD}}$ Deasserted to $\overline{\text{WR}}$ Asserted | t_{RDWR} | | 0.14 | 0.50 | MDAR, BMDAR, RWSH, WWSS | ns |
| | | | -0.57 | 0.69 | | |

1. N/A since device captures data before it deasserts $\overline{\text{RD}}$

2. If RWSS = RWSH = 0, RD does not deassert during back-to-back reads and D=0.00 should be used.

4.7 Reset, Stop, Wait, Mode Select, and Interrupt Timing

Table 4-8 Reset, Stop, Wait, Mode Select, and Interrupt Timing^{1, 2}

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{C}$, $C_L \leq 50\text{ pF}$, $f_{op} = 120\text{ MHz}$

| Characteristic | Symbol | Min | Max | Unit | See Figure |
|---|------------------|--------|------|------|------------|
| $\overline{\text{RESET}}$ Assertion to Address, Data and Control Signals High Impedance | t_{RAZ} | — | 11 | ns | 4-11 |
| Minimum $\overline{\text{RESET}}$ Assertion Duration ³ | t_{RA} | 30 | — | ns | 4-11 |
| $\overline{\text{RESET}}$ Deassertion to First External Address Output | t_{RDA} | — | 120T | ns | 4-11 |
| Edge-sensitive Interrupt Request Width | t_{IRW} | 1T + 3 | — | ns | 4-12 |

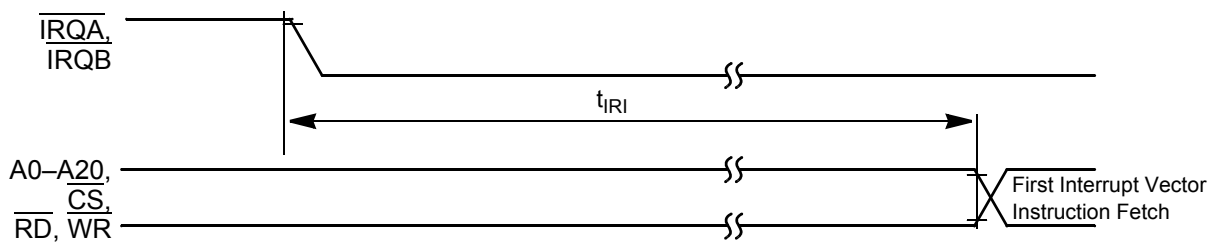


Figure 4-14 Interrupt from Wait State Timing

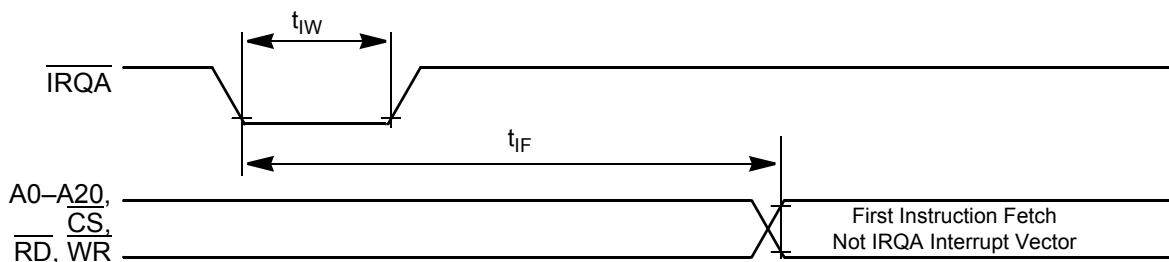


Figure 4-15 Recovery from Stop State Using Asynchronous Interrupt Timing

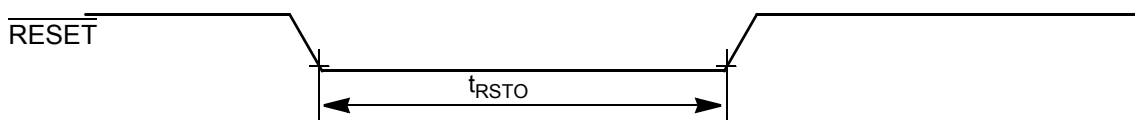


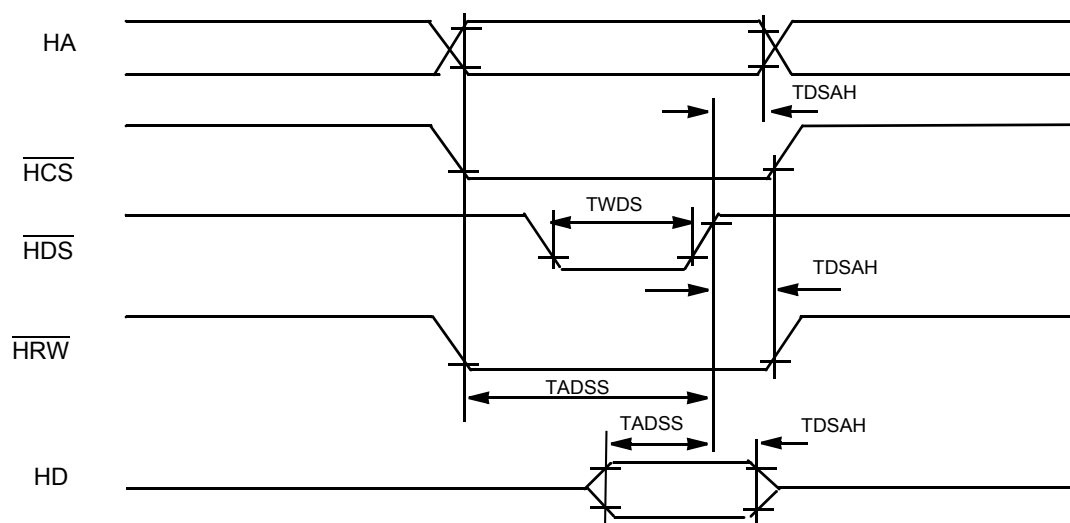
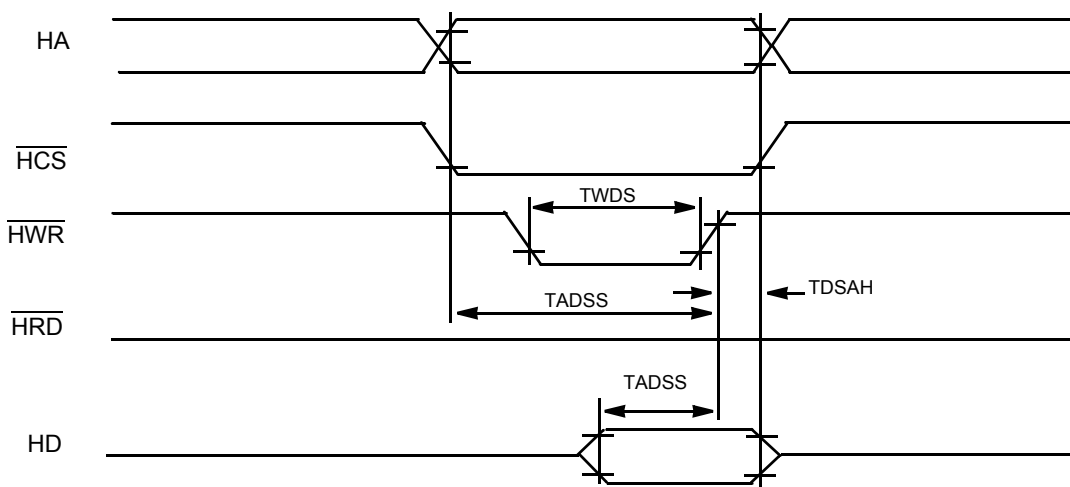
Figure 4-16 Reset Output Timing

4.8 Host Interface Port

Table 4-9 Host Interface Port Timing¹

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{ C}$, $C_L \leq 50\text{ pF}$, $f_{op} = 120\text{ MHz}$

| Characteristic | Symbol | Min | Max | Unit | See Figure |
|-------------------|----------|-----|-----|------|---------------|
| Access time | TACKDV | — | 13 | ns | 4-17 |
| Disable time | TACKDZ | 3 | — | ns | 4-17 |
| Time to disassert | TACKREQH | 3.5 | 9 | ns | 4-17, 4-20 |
| Lead time | TREQACKL | 0 | — | ns | 4-17 4-20 |

**Figure 4-21 Single Strobe Write Mode****Figure 4-22 Dual Strobe Write Mode**

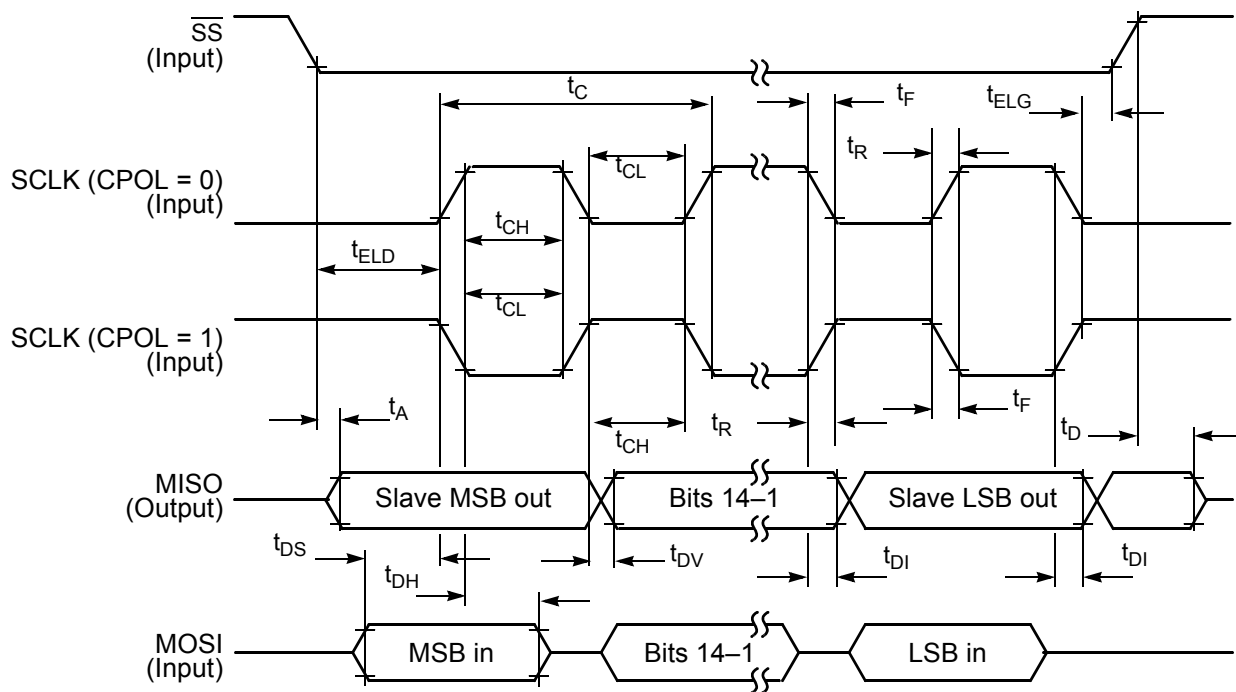


Figure 4-25 SPI Slave Timing (CPHA = 0)

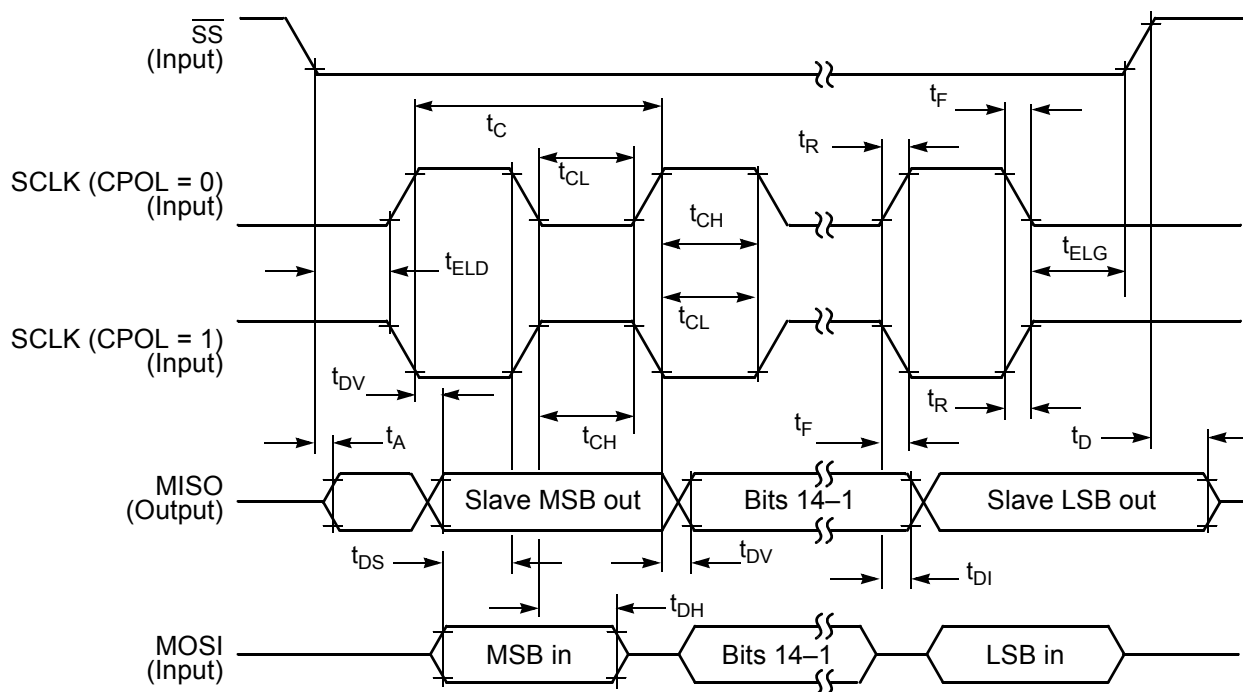


Figure 4-26 SPI Slave Timing (CPHA = 1)

4.10 Quad Timer Timing

Table 4-11 Quad Timer Timing^{1, 2}

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{C}$, $C_L \leq 50\text{ pF}$, $f_{op} = 120\text{ MHz}$

| Characteristic | Symbol | Min | Max | Unit |
|------------------------------|-------------|----------|-----|------|
| Timer input period | P_{IN} | $2T + 3$ | — | ns |
| Timer input high/low period | P_{INHL} | $1T + 3$ | — | ns |
| Timer output period | P_{OUT} | $2T - 3$ | — | ns |
| Timer output high/low period | P_{OUTHL} | $1T - 3$ | — | ns |

1. In the formulas listed, T = clock cycle. For $f_{op} = 120\text{ MHz}$ operation and $f_{ipb} = 60\text{ MHz}$, $T = 8.33\text{ ns}$.
2. Parameters listed are guaranteed by design.

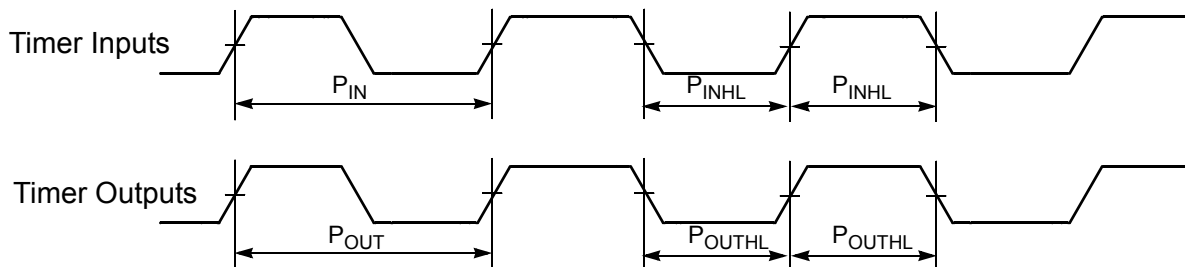


Figure 4-27 Timer Timing

4.11 Enhanced Synchronous Serial Interface (ESSI) Timing

Table 4-12 ESSI Master Mode¹ Switching Characteristics

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{C}$, $C_L \leq 50\text{ pF}$, $f_{op} = 120\text{ MHz}$

| Parameter | Symbol | Min | Typ | Max | Units |
|--|--------------|-------------------|-----|--------|-------|
| SCK frequency | f_s | — | — | 15^2 | MHz |
| SCK period ³ | t_{SCKW} | 66.7 | — | — | ns |
| SCK high time | t_{SCKH} | 33.4 ⁴ | — | — | ns |
| SCK low time | t_{SCKL} | 33.4 ⁴ | — | — | ns |
| Output clock rise/fall time | — | — | 4 | — | ns |
| Delay from SCK high to SC2 (bl) high - Master ⁵ | t_{TFSBHM} | -1.0 | — | 1.0 | ns |

Table 4-12 ESSI Master Mode¹ Switching Characteristics (Continued)

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{C}$, $C_L \leq 50\text{ pF}$, $f_{op} = 120\text{ MHz}$

| Parameter | Symbol | Min | Typ | Max | Units |
|--|--------------|------|-----|-----|-------|
| Delay from SCK high to SC2 (wl) high - Master ⁵ | t_{TFSWHM} | -1.0 | — | 1.0 | ns |
| Delay from SC0 high to SC1 (bl) high - Master ⁵ | t_{RFSBHM} | -1.0 | — | 1.0 | ns |
| Delay from SC0 high to SC1 (wl) high - Master ⁵ | t_{RFSWHM} | -1.0 | — | 1.0 | ns |
| Delay from SCK high to SC2 (bl) low - Master ⁵ | t_{TFSBLM} | -1.0 | — | 1.0 | ns |
| Delay from SCK high to SC2 (wl) low - Master ⁵ | t_{TFSWLM} | -1.0 | — | 1.0 | ns |
| Delay from SC0 high to SC1 (bl) low - Master ⁵ | t_{RFSBLM} | -1.0 | — | 1.0 | ns |
| Delay from SC0 high to SC1 (wl) low - Master ⁵ | t_{RFSWLM} | -1.0 | — | 1.0 | ns |
| SCK high to STD enable from high impedance - Master | t_{TXEM} | -0.1 | — | 2 | ns |
| SCK high to STD valid - Master | t_{TXVM} | -0.1 | — | 2 | ns |
| SCK high to STD not valid - Master | t_{TXNVM} | -0.1 | — | — | ns |
| SCK high to STD high impedance - Master | t_{TXHIM} | -4 | — | 0 | ns |
| SRD Setup time before SC0 low - Master | t_{SM} | 4 | — | — | ns |
| SRD Hold time after SC0 low - Master | t_{HM} | 4 | — | — | ns |
| Synchronous Operation (in addition to standard internal clock parameters) | | | | | |
| SRD Setup time before SCK low - Master | t_{TSM} | 4 | — | — | ns |
| SRD Hold time after SCK low - Master | t_{THM} | 4 | — | — | ns |

1. Master mode is internally generated clocks and frame syncs
2. Max clock frequency is $IP_clk/4 = 60\text{ MHz} / 4 = 15\text{ MHz}$ for an 120MHz part.
3. All the timings for the ESSI are given for a non-inverted serial clock polarity ($TSCKP=0$ in SCR2 and $RSCKP=0$ in SCSR) and a non-inverted frame sync ($TFSl=0$ in SCR2 and $RFSI=0$ in SCSR). If the polarity of the clock and/or the frame sync have been inverted, all the timings remain valid by inverting the clock signal SCK/SC0 and/or the frame sync SC2/SC1 in the tables and in the figures.
4. 50 percent duty cycle
5. bl = bit length; wl = word length

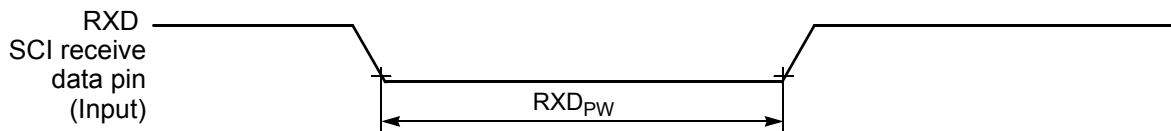


Figure 4-30 RXD Pulse Width

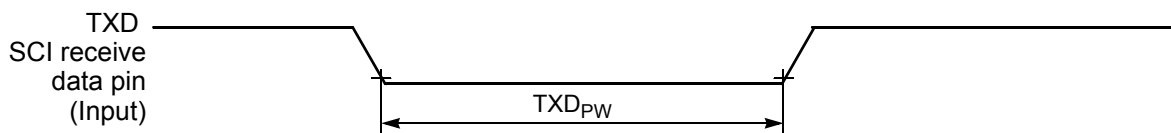


Figure 4-31 TXD Pulse Width

4.13 JTAG Timing

Table 4-15 JTAG Timing^{1, 3}

Operating Conditions: $V_{SS} = V_{SSIO} = V_{SSA} = 0\text{ V}$, $V_{DD} = 1.62\text{--}1.98\text{ V}$, $V_{DDIO} = V_{DDA} = 3.0\text{--}3.6\text{ V}$, $T_A = -40^\circ\text{ to }+120^\circ\text{ C}$, $C_L \leq 50\text{ pF}$, $f_{op} = 120\text{ MHz}$

| Characteristic | Symbol | Min | Max | Unit |
|---|------------|------|-----|------|
| TCK frequency of operation ² | f_{OP} | DC | 30 | MHz |
| TCK cycle time | t_{CY} | 33.3 | — | ns |
| TCK clock pulse width | t_{PW} | 16.6 | — | ns |
| TMS, TDI data setup time | t_{DS} | 3 | — | ns |
| TMS, TDI data hold time | t_{DH} | 3 | — | ns |
| TCK low to TDO data valid | t_{DV} | — | 12 | ns |
| TCK low to TDO tri-state | t_{TS} | — | 10 | ns |
| $\overline{\text{TRST}}$ assertion time | t_{TRST} | 35 | — | ns |
| $\overline{\text{DE}}$ assertion time | t_{DE} | 4T | — | ns |

1. Timing is both wait state and frequency dependent. For the values listed, T = clock cycle. For 120MHz operation, $T = 8.33\text{ ns}$.

2. TCK frequency of operation must be less than 1/4 the processor rate.

3. Parameters listed are guaranteed by design.

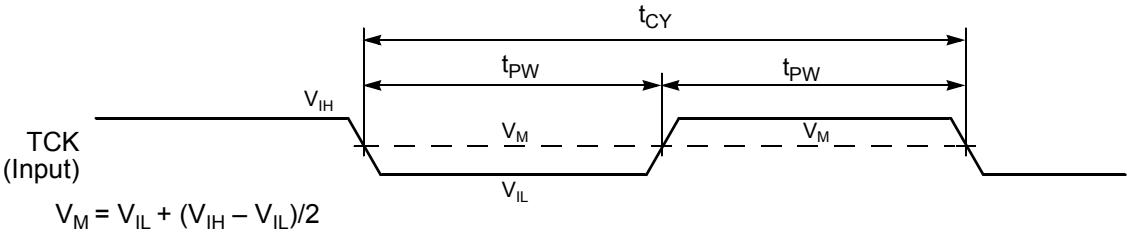


Figure 4-32 Test Clock Input Timing Diagram

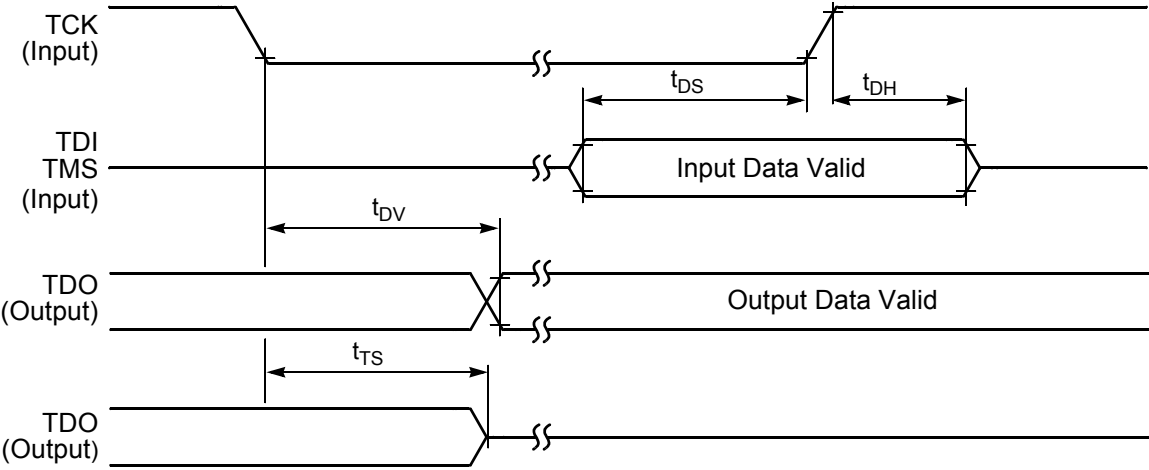


Figure 4-33 Test Access Port Timing Diagram



Figure 4-34 \overline{TRST} Timing Diagram



Figure 4-35 Enhanced OnCE—Debug Event

Part 6 Design Considerations

6.1 Thermal Design Considerations

An estimation of the chip junction temperature, T_J , in °C can be obtained from the equation:

$$\text{Equation 1: } T_J = T_A + (P_D \times R_{\theta JA})$$

Where:

T_A = ambient temperature °C

$R_{\theta JA}$ = package junction-to-ambient thermal resistance °C/W

P_D = power dissipation in package

Historically, thermal resistance has been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$\text{Equation 2: } R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

Where:

$R_{\theta JA}$ = package junction-to-ambient thermal resistance °C/W

$R_{\theta JC}$ = package junction-to-case thermal resistance °C/W

$R_{\theta CA}$ = package case-to-ambient thermal resistance °C/W

$R_{\theta JC}$ is device-related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For example, the user can change the air flow around the device, add a heat sink, change the mounting arrangement on the Printed Circuit Board (PCB), or otherwise change the thermal dissipation capability of the area surrounding the device on the PCB. This model is most useful for ceramic packages with heat sinks; some 90% of the heat flow is dissipated through the case to the heat sink and out to the ambient environment. For ceramic packages, in situations where the heat flow is split between a path to the case and an alternate path through the PCB, analysis of the device thermal performance may need the additional modeling capability of a system level thermal simulation tool.

The thermal performance of plastic packages is more dependent on the temperature of the PCB to which the package is mounted. Again, if the estimations obtained from $R_{\theta JA}$ do not satisfactorily answer whether the thermal performance is adequate, a system level model may be appropriate.

A complicating factor is the existence of three common definitions for determining the junction-to-case thermal resistance in plastic packages:

- Measure the thermal resistance from the junction to the outside surface of the package (case) closest to the chip mounting area when that surface has a proper heat sink. This is done to minimize temperature variation across the surface.
- Measure the thermal resistance from the junction to where the leads are attached to the case. This definition is approximately equal to a junction to board thermal resistance.
- Use the value obtained by the equation $(T_J - T_T)/P_D$ where T_T is the temperature of the package case determined by a thermocouple.

As noted above, the junction-to-case thermal resistances quoted in this data sheet are determined using the first definition. From a practical standpoint, that value is also suitable for determining the junction temperature from a case thermocouple reading in forced convection environments. In natural convection, using the junction-to-case

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